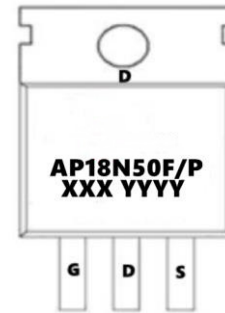
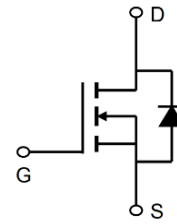


500V N-Channel Enhancement Mode MOSFET

Description

The AP18N50F/P is silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.



General Features

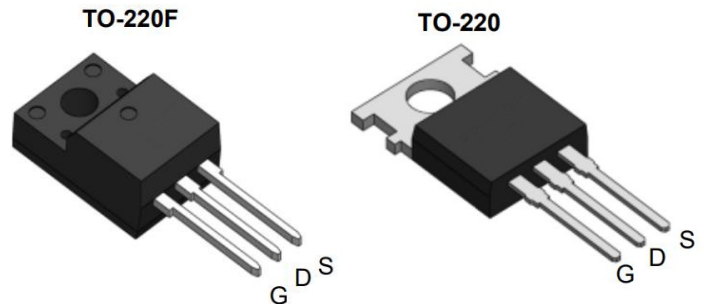
$V_{DS} = 500V$ $I_D = 18A$

$R_{DS(ON)} < 350m\Omega$ @ $V_{GS}=10V$ (Type: **280mΩ**)

Application

Uninterruptible Power Supply(UPS)

Power Factor Correction (PFC)



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP18N50F	TO-220F-3L	AP18N50F XXX YYYY	1000
AP18N50P	TO-220-3L	AP18N50P XXX YYYY	1000

Absolute Maximum Ratings ($T_C=25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Value		Unit
		TO-220F	TO-220	
V_{DS}	Drain-Source Voltage ($V_{GS} = 0V$)	500		V
I_D	Continuous Drain Current	18		A
I_{DM}	Pulsed Drain Current (note1)	65		A
V_{GS}	Gate-Source Voltage	± 30		V
E_{AS}	Single Pulse Avalanche Energy (note2)	405		mJ
I_{AR}	Avalanche Current (note1)	16		A
E_{AR}	Repetitive Avalanche Energy note1)	5		mJ
P_D	Power Dissipation ($T_C = 25^{\circ}C$)	29.8		W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	-55~+150		$^{\circ}C$
R_{thJC}	Thermal Resistance, Junction-to-Case	3.92		$^{\circ}C/W$
R_{thJA}	Thermal Resistance, Junction-to-Ambient	62.5		$^{\circ}C/W$



500V N-Channel Enhancement Mode MOSFET

Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	500			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D =250μA, Referenced to 25°C		0.51		V/°C
IDSS	Zero Gate Voltage Drain Current	V _{DS} = 500 V, V _{GS} = 0 V			1	μA
		V _{DS} = 400 V, TC = 125°C			10	μA
IGSSF	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
IGSSR	Gate-Body Leakage Current, Reverse	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
VGS(TH)	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250 uA	3.0		5.0	V
RDS(On)	Drain-Source On-state Resistance	V _{GS} =10 V, I _D = 8 A, T _J = 25°C		280	350	mΩ
gFS	Forward Transconductance	V _{DS} = 40 V, I _D = 8 A (Note 4)		16		S
C _{iss}	Input Capacitance	V _{DS} = 25V, V _{GS} = 0V, f = 1.0 MHz		1670		pF
C _{oss}	Output Capacitance			247		pF
C _{rss}	Reverse Transfer Capacitance			6.8		pF
td(on)	Turn On Delay Time	V _{DD} =250V, I _D =16A, R _G = 25 Ω (Note 4, 5)		27		ns
t _r	Rising Time			45		ns
td(off)	Turn Off Delay Time			61		ns
t _f	Fall Time			38		ns
Q _g	Total Gate Charge	V _{DS} = 250 V, I _D = 16A, V _{GS} = 10 V (Note 4, 5)		31		nC
Q _{gs}	Gate-Source Charge			13		nC
Q _{gd}	Gate-Drain Charge			9		nC
ISM	Maximum Pulsed Drain-Source Diode Forward Current				64	A
V _{SD}	Diode Forward Voltage	V _{GS} = 0 V, I _S = 16 A			1.4	V
trr	Reverse Recovery Time	V _{GS} = 0 V, I _S = 16 A, dI _F / dt = 100 A/μs Note 4)		342		ns
Q _{rr}	Reverse Recovery Charge			4.0		μC

Note :

- 1、 The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- 2、 The EAS data shows Max. rating . L=4.1Mh IAS=16A, VDD=50V, RG=25Ω, Starting T_J = 25 °C
- 3、 The test condition is Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%
- 4、 The power dissipation is limited by 150°C junction temperature
- 5、 The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

500V N-Channel Enhancement Mode MOSFET

Typical Characteristics

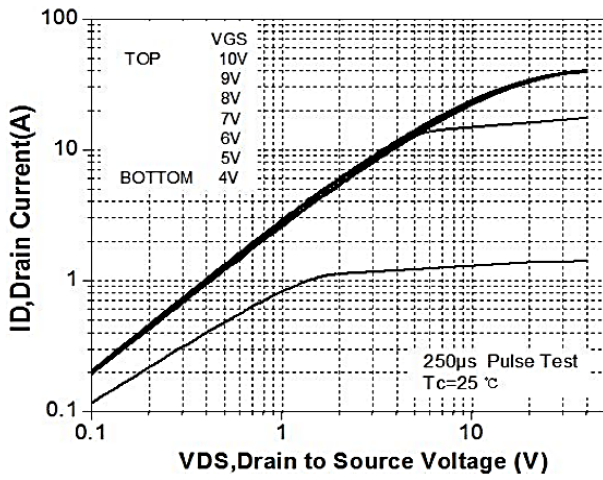


Figure 1. On-Region Characteristics

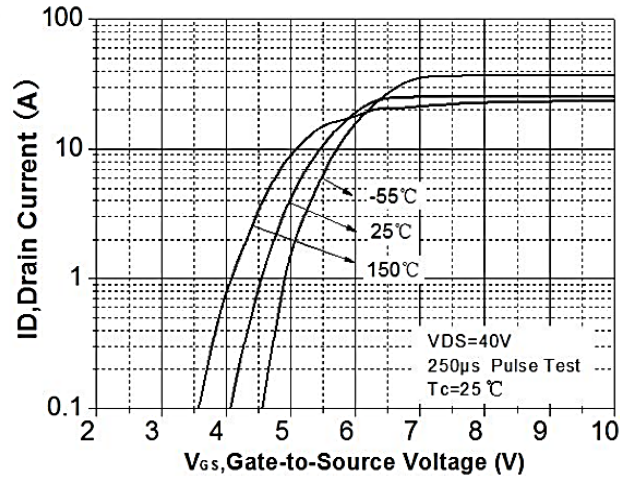


Figure 2. Transfer Characteristics

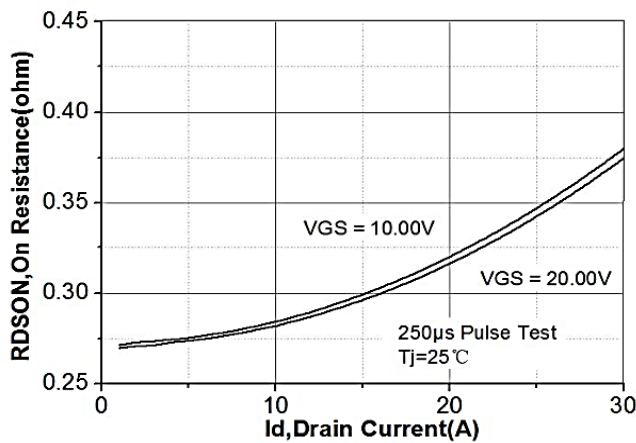


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

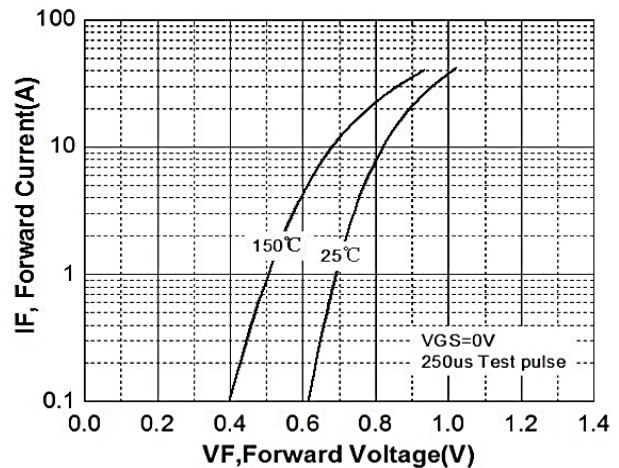


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

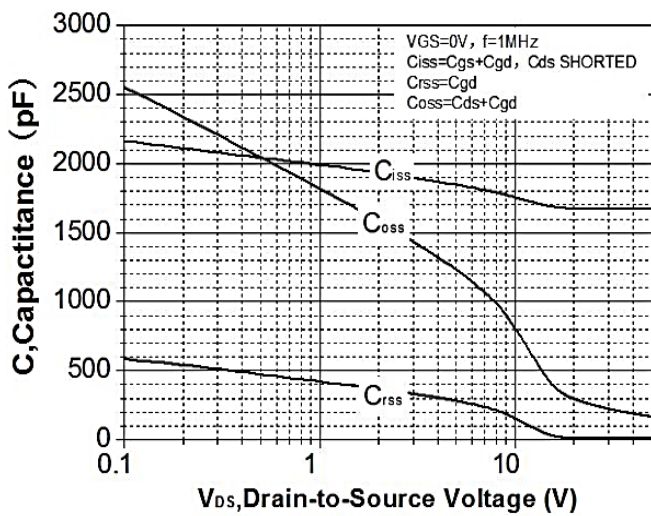


Figure 5. Capacitance Characteristics

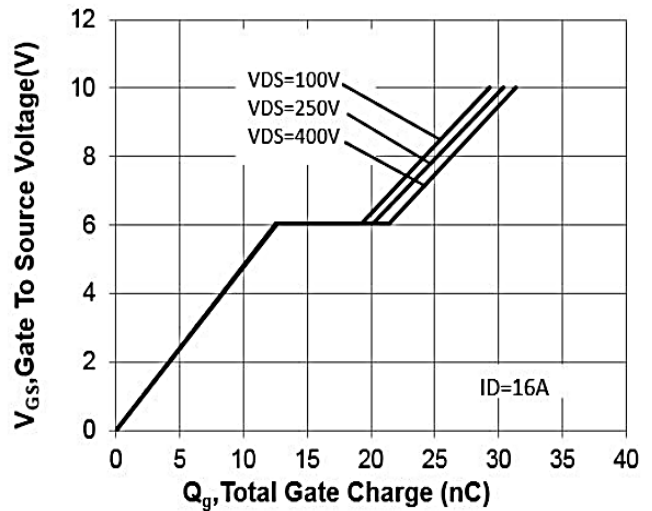


Figure 6. Gate Charge Characteristics

500V N-Channel Enhancement Mode MOSFET

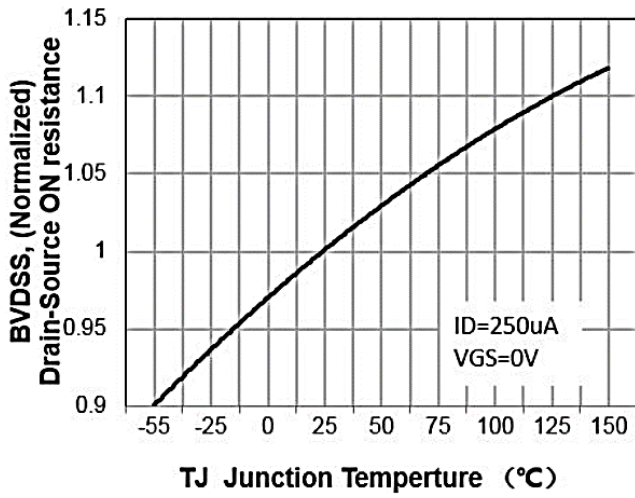


Figure 7. Breakdown Voltage Variation vs Temperature

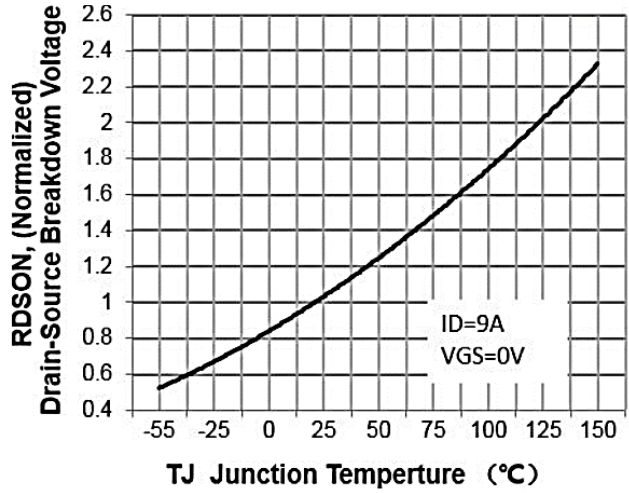


Figure 8. On-Resistance Variation vs Temperature

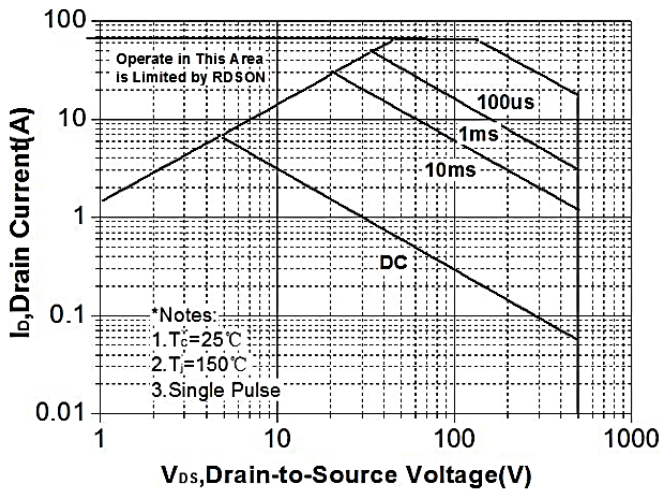


Figure 9. Maximum Safe Operating Area

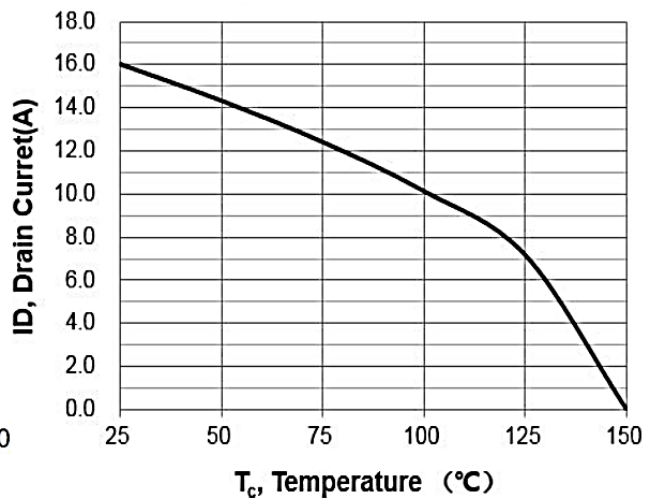


Figure 10. Maximum Drain Current vs Case Temperature

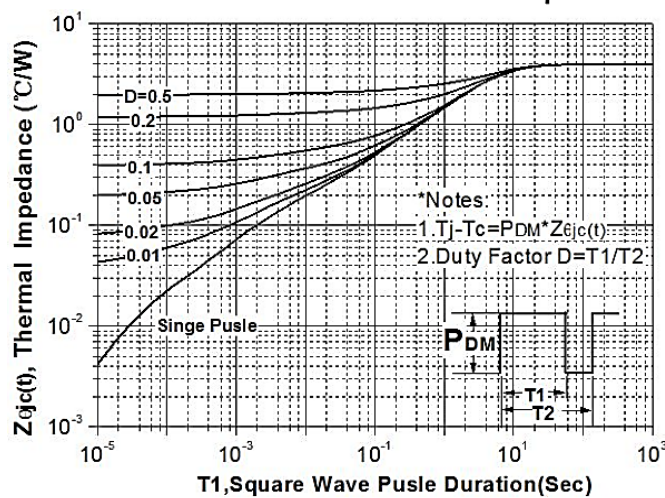
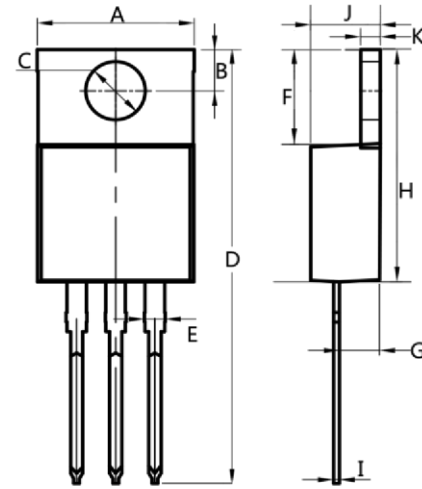


Figure 11. Transient Thermal Response Curve

500V N-Channel Enhancement Mode MOSFET

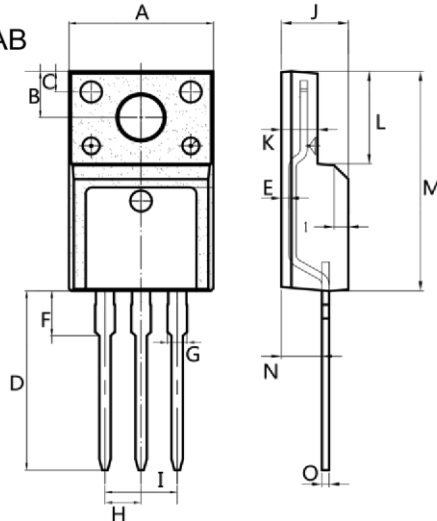
TO-220AB



Dim.	Min.	Max.
A	10.0	10.4
B	2.5	3.0
C	3.5	4.0
D	28.0	30.0
E	1.1	1.5
F	6.2	6.6
G	2.9	3.3
H	15.0	16.0
I	0.35	0.45
J	4.3	4.7
K	1.2	1.4

All Dimensions in millimeter

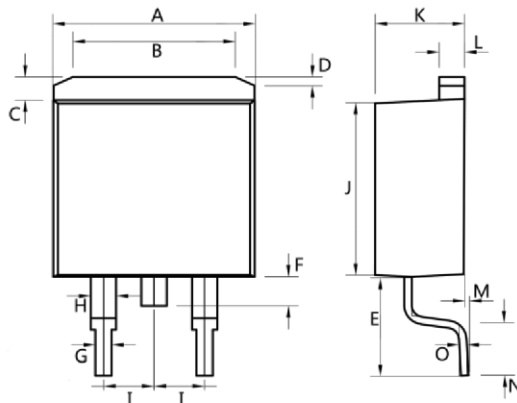
ITO-220AB



Dim.	Min.	Max.
A	9.9	10.3
B	2.9	3.5
C	1.15	1.45
D	12.75	13.25
E	0.55	0.75
F	3.1	3.5
G	1.25	1.45
H	Typ	2.54
I	Typ	5.08
J	4.55	4.75
K	2.4	2.7
L	6.35	6.75
M	15.0	16.0
N	2.75	3.15
O	0.45	0.60

All Dimensions in millimeter

TO-263



Dim.	Min.	Max.
A	10.0	10.5
B	7.25	7.75
C	1.3	1.5
D	0.55	0.75
E	5.0	6.0
F	1.4	1.6
G	0.75	0.95
H	1.15	1.35
I	Typ	2.54
J	8.4	8.6
K	4.4	4.6
L	1.25	1.45
M	0.02	0.1
N	2.4	2.8
O	0.35	0.45

All Dimensions in millimeter